



Advanced Polarimetry and Polarimetric Imaging

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Message from the Guest Editors

As a fundamental property of the light wave, polarization information can be used to reveal the light's and target's physical properties, such as the material, thickness, surface features, refractive index, etc. Therefore, improving the performance of polarimetry and polarimetric imagers and exploring related applications are still necessary to address existing challenges and expand the potential of polarimetric imaging.

This Special Issue aims to provide a platform for researchers to share and discuss important discoveries, theoretical and experimental advances, technical breakthroughs, methodological innovations, application developments, viewpoints, and perspectives with the community of polarized light. All theoretical, numerical, and experimental papers are welcome. Topics include, but are not limited to, the following:

- Fundamentals of polarized light;
- Polarimetry/ellipsometry systems and methods;
- Polarimetric imaging systems and processing methods;
- Applications of polarimetry, ellipsometry, and polarimetric imaging;
- Polarization information meets artificial intelligence.

